

# 8K x 8 Bit Fast Static Random Access Memory

The MCM6164/MCM61L64 is a 65,536 bit static random access memory organized as 8192 words of 8 bits, fabricated using Motorola's second-generation high-performance silicon-gate CMOS (HCMOS III) technology. Static design eliminates the need for external clocks or timing strobes, while CMOS circuitry reduces power consumption and provides greater reliability.

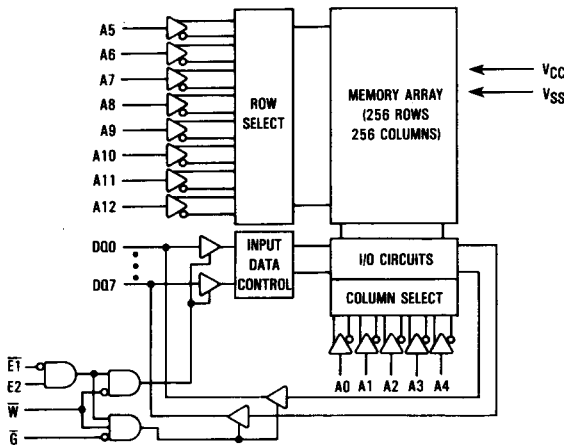
The chip enable pins ( $\overline{E1}$  and E2) are not clocks. Either pin, when asserted false, causes the part to enter a low power standby mode. The part will remain in standby mode until both pins are asserted true again. The availability of active high and active low chip enable pins provides more system design flexibility than single chip enable devices.

The MCM6164/MCM61L64 is available in a 600 mil, 28 pin ceramic dual-in-line package, with JEDEC standard pinout.

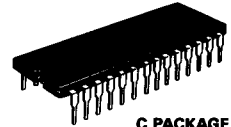
- Single 5 V Supply,  $\pm 10\%$
- 8K x 8 Organization
- Fully Static — No Clock or Timing Strokes Necessary
- Fast Access Time — 45, 55 ns (Maximum)
- Low Power Dissipation — 495, 440 mW (Maximum, Active)
- Low Power/Data Retention Version (MCM61L64)
- Fully TTL Compatible
- Three State Data Outputs
- Also Available in Industrial Temperature Range ( $-40$  to  $85^\circ\text{C}$ ) as MCM6164C

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**BLOCK DIAGRAM**



## MCM6164 MCM61L64



**C PACKAGE  
CERAMIC  
CASE 733**

**PIN ASSIGNMENT**

NC	1	28	VCC
A12	2	27	$\overline{W}$
A7	3	26	E2
A6	4	25	A8
A5	5	24	A9
A4	6	23	A11
A3	7	22	$\overline{G}$
A2	8	21	A10
A1	9	20	$\overline{E1}$
A0	10	19	D07
D00	11	18	D06
D01	12	17	D05
D02	13	16	D04
VSS	14	15	D03

**PIN NAMES**

A0-A12	Address
$\overline{W}$	Write Enable
$\overline{E1}$ , E2	Chip Enable
$\overline{G}$	Output Enable
D00-D07	Data Input/Output
VCC	+5 V Power Supply
VSS	Ground
NC	No Connection

**TRUTH TABLE**

$\overline{E1}$	E2	$\overline{G}$	$\overline{W}$	Mode	Supply Current	I/O Pin
H	X	X	X	Not Selected	$I_{SB}$	High Z
X	L	X	X	Not Selected	$I_{SB}$	High Z
L	H	H	H	Output Disabled	$I_{CC}$	High Z
L	H	L	H	Read	$I_{CC}$	$D_{out}$
L	H	X	L	Write	$I_{CC}$	$D_{in}$

X = don't care

**ABSOLUTE MAXIMUM RATINGS (See Note)**

Rating	Symbol	Value	Unit
Power Supply Voltage	$V_{CC}$	-0.5 to +7.0	V
Voltage Relative to $V_{SS}$ for Any Pin Except $V_{CC}$	$V_{in}, V_{out}$	-0.5 to $V_{CC} + 0.5$	V
Output Current (per I/O)	$I_{out}$	$\pm 20$	mA
Power Dissipation ( $T_A = 25^\circ C$ )	$P_D$	1.0	W
Temperature Under Bias	$T_{bias}$	-10 to +85	$^\circ C$
Operating Temperature	$T_A$	0 to +70	$^\circ C$
Storage Temperature	$T_{stg}$	-65 to +150	$^\circ C$

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit.



NOTE: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPERATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.

**DC OPERATING CONDITIONS AND CHARACTERISTICS**  
( $V_{CC} = 5.0 V \pm 10\%$ ,  $T_A = 0$  to  $70^\circ C$ , Unless Otherwise Noted)

**RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage (Operating Voltage Range)	$V_{CC}$	4.5	5.0	5.5	V
Input High Voltage	$V_{IH}$	2.2	—	$V_{CC} + 0.3$	V
Input Low Voltage	$V_{IL}$	-0.3*	—	0.8	V

\* $V_{IL}(\min) = -0.3 V$  dc,  $V_{IL}(\min) = -3.0 V$  (pulse width  $\leq 20$  ns)

**DC CHARACTERISTICS**

Characteristic	Symbol	Min	Typ	Max	Unit
Input Leakage Current (All Inputs, $V_{in} = 0$ to $V_{CC}$ )	$I_{kg(I)}$	—	<0.01	$\pm 1.0$	$\mu A$
Output Leakage Current ( $\overline{E1} = V_{IH}$ , $E2 = V_{IL}$ , or $\overline{G} = V_{IH}$ , $V_{out} = 0$ to $V_{CC}$ )	$I_{kg(O)}$	—	<0.01	$\pm 1.0$	$\mu A$
Power Supply Current ( $\overline{E1} = V_{IL}$ , $E2 = V_{IH}$ , $I_{out} = 0$ )	$I_{CC}$	—	50 40	90 80	mA
Standby Current ( $\overline{E1} = V_{IH}$ or $E2 = V_{IL}$ )	$I_{SB1}$	—	1.3	3.0	mA
Standby Current ( $\overline{E1} \geq V_{CC} - 0.2 V$ or $E2 \leq 0.2 V$ )	MCM6164 MCM61L64	—	— 5	1.0 50	mA $\mu A$
Output Low Voltage ( $I_{OL} = 8.0$ mA)	$V_{OL}$	—	0.15	0.4	V
Output High Voltage ( $I_{OH} = -4.0$ mA)	$V_{OH}$	2.4	3.0	—	V

Typical values are referenced to  $T_A = 25^\circ C$  and  $V_{CC} = 5.0 V$

**CAPACITANCE** ( $f = 1.0$  MHz,  $T_A = 25^\circ C$ , Periodically Sampled Rather Than 100% Tested)

Characteristic	Symbol	Max	Unit
Input Capacitance	All Inputs Except DQ $C_{in}$	6	pF
Input/Output Capacitance	DQ $C_{I/O}$	8	pF

AC OPERATING CONDITIONS AND CHARACTERISTICS

(VCC = 5 V ± 10%, TA = 0 to +70°C, Unless Otherwise Noted)

Input Timing Measurement Reference Level . . . . . 1.5 V  
 Input Pulse Levels . . . . . 0 to 3.0 V  
 Input Rise/Fall Time . . . . . 5 ns

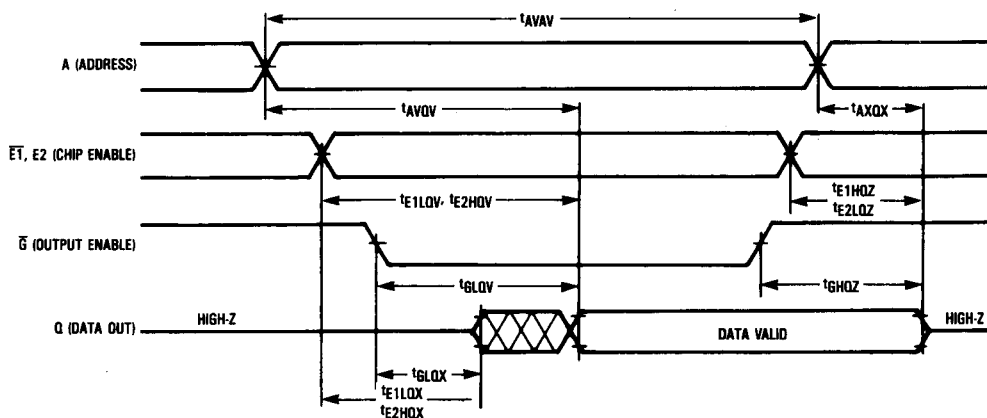
Output Timing Measurement Reference Level . . . 0.8 V and 2.0 V  
 Output Load . . . . . Figure 1

READ CYCLE (See Note 1)

Characteristic	Symbol	Alt Symbol	MCM6164-65 MCM61L64-65		MCM6164-55 MCM61L64-55		Unit	Notes
			Min	Max	Min	Max		
Read Cycle Time	tAVAV	tRC	45	—	55	—	ns	—
Address Cycle Time	tAVQV	tAA	—	45	—	55	ns	—
E1 Access Time	tE1LOV	tAC1	—	45	—	55	ns	—
E2 Access Time	tE2HOV	tAC2	—	45	—	55	ns	—
$\bar{G}$ Access Time	tGLOV	tOE	—	20	—	25	ns	—
Output Hold from Address Change	tAXOX	tOH	5	—	5	—	ns	—
Chip Enable to Output Low-Z	tE1LOX, tE2HOX	tCLZ	5	—	5	—	ns	2, 3
Output Enable to Output Low-Z	tGLOX	tOLZ	0	—	0	—	ns	2, 3
Chip Enable to Output High-Z	tE1HOZ, tE2LOZ	tCHZ	0	20	0	20	ns	2, 3
Output Enable to Output High-Z	tGHOZ	tOHZ	0	20	0	20	ns	2, 3

NOTES:

1.  $\bar{W}$  is high at all times for read cycles.
2. All high-Z and low-Z parameters are considered in a high or low impedance state when the output has made a 500 mV transition from the previous steady state voltage.
3. Periodically sampled rather than 100% tested.



TIMING LIMITS

The table of timing values shows either a minimum or a maximum limit for each parameter. Input requirements are specified from the external system point of view. Thus, address setup time is shown as a minimum since the system must supply at least that much time (even though most devices do not require it). On the other hand, responses from the memory are specified from the device point of view. Thus, the access time is shown as a maximum since the device never provides data later than that time.

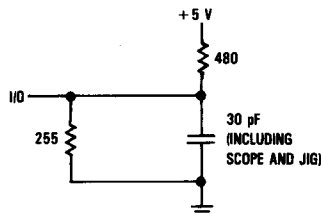


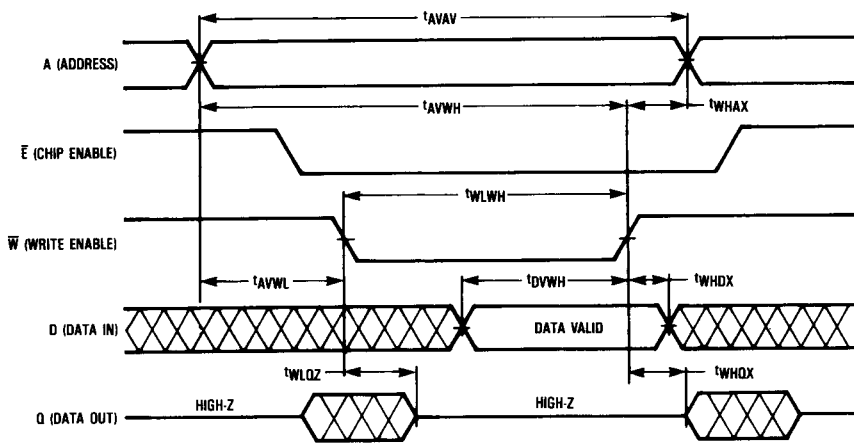
Figure 1. Test Load

WRITE CYCLE 1 ( $\bar{W}$  CONTROLLED) (See Note 1)

Characteristic	Symbol	Alt Symbol	MCM6164-45 MCM61L64-45		MCM6164-55 MCM61L64-55		Unit	Notes
			Min	Max	Min	Max		
			Write Cycle Time	$t_{AVAV}$	$t_{WC}$	45		
Address Setup Time	$t_{AVWL}$	$t_{AS}$	0	—	0	—	ns	—
Address Valid to End of Write	$t_{AVWH}$	$t_{AW}$	40	—	50	—	ns	—
Write Pulse Width	$t_{WLWH}$	$t_{WP}$	25	—	30	—	ns	2
Data Valid to End of Write	$t_{DVWH}$	$t_{DW}$	20	—	25	—	ns	—
Data Hold Time	$t_{WHDX}$	$t_{DH}$	0	—	0	—	ns	3
Write Low to Output in High-Z	$t_{WLQZ}$	$t_{WHZ}$	0	20	0	20	ns	4, 5
Write High to Output Low-Z	$t_{WHQZ}$	$t_{QW}$	5	—	5	—	ns	4, 5
Write Recovery Time	$t_{WHAX}$	$t_{WR}$	0	—	0	—	ns	—

NOTES:

1. A write cycle starts at the latest transition of a low  $\bar{E}1$ , low  $\bar{W}$  or high  $E2$ . A write cycle ends at the earliest transition of a high  $E1$ , high  $W$  or low  $E2$ .
2. If  $\bar{W}$  goes low coincident with or prior to  $\bar{E}1$  low or  $E2$  high then the outputs will remain in a high impedance state.
3. During this time the output pins may be in the output state. Signals of opposite phase to the outputs must not be applied at this time.
4. All high-Z and low-Z parameters are considered in a high or low impedance state when the output has made a 500 mV transition from the previous steady state voltage.
5. Periodically sampled rather than 100% tested.



TYPICAL CHARACTERISTICS

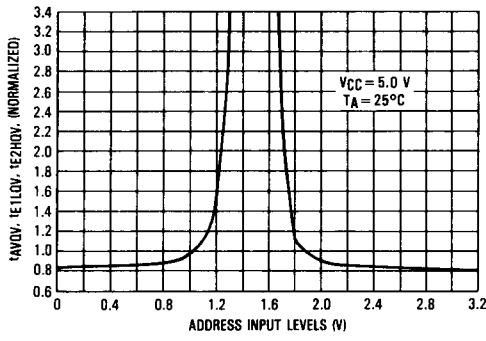


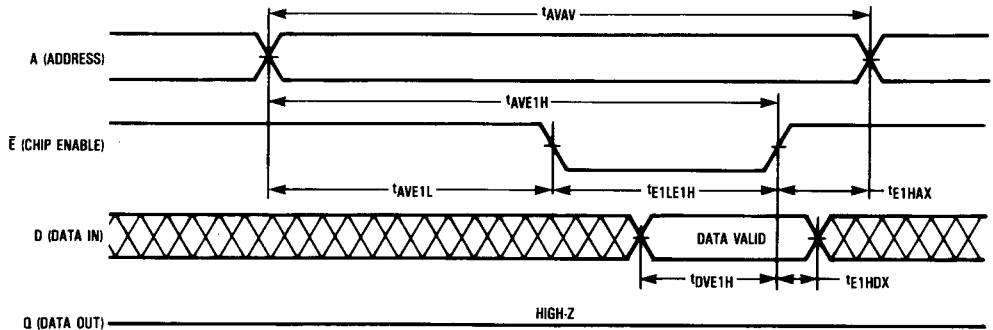
Figure 2. Access Time Versus Address Input Levels

WRITE CYCLE 2 (ENABLE CONTROLLED) (See Notes 1 and 2)

Characteristic	Symbol	Alt Symbol	MCM6164-46 MCM61L64-46		MCM6164-56 MCM61L64-56		Unit	Notes
			Min	Max	Min	Max		
			Write Cycle Time	$t_{AVAV}$	$t_{WC}$	45		
Address Setup Time	$t_{AVE1L}$	$t_{AS}$	0	—	0	—	ns	—
Address Valid to End of Write	$t_{AVE1H}$	$t_{AW}$	40	—	50	—	ns	—
Chip Enable to End of Write	$t_{E1LE1H}$	$t_{CW}$	40	—	50	—	ns	3
Data Valid to End of Write	$t_{DVE1H}$	$t_{DW}$	20	—	25	—	ns	—
Data Hold Time	$t_{E1HDX}$	$t_{DH}$	0	—	0	—	ns	4
Write Recovery Time	$t_{E1HAX}$	$t_{WR}$	0	—	0	—	ns	—

NOTES:

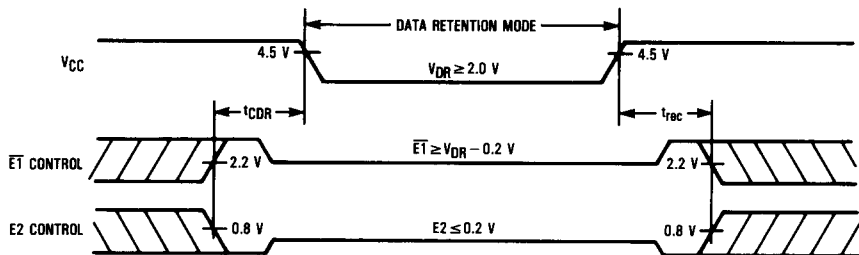
1. A write cycle starts at the latest transition of a low  $\overline{E1}$ , low  $\overline{W}$  or high  $E2$ . A write cycle ends at the earliest transition of a high  $\overline{E1}$ , high  $\overline{W}$  or low  $E2$ .
2.  $\overline{E1}$  and  $E2$  timings are identical when  $E2$  signals are inverted.
3. If  $\overline{W}$  goes low coincident with or prior to  $\overline{E1}$  low or  $E2$  high then the outputs will remain in a high impedance state.
4. During this time the output pins may be in the output state. Signals of opposite phase to the outputs must not be applied at this time.



LOW  $V_{CC}$  DATA RETENTION CHARACTERISTICS ( $T_A = 0$  to  $+70^\circ\text{C}$ ) (MCM61L64 Only)

Characteristic	Symbol	Min	Typ	Max	Unit
$V_{CC}$ for Data Retention ( $\overline{E1} \geq V_{CC} - 0.2 \text{ V}$ or $E2 \leq 0.2 \text{ V}$ , $V_{in} \geq V_{CC} - 0.2 \text{ V}$ or $V_{in} \leq 0.2 \text{ V}$ )	$V_{DR}$	2.0	1.0	7.0	V
Data Retention Current ( $V_{CC} = 3.0 \text{ V}$ , $\overline{E1} \geq 2.8 \text{ V}$ or $E2 \leq 0.2 \text{ V}$ , $V_{in} \geq 2.8 \text{ V}$ or $V_{in} \leq 0.2 \text{ V}$ )	$I_{CCDR}$	—	10	30	$\mu\text{A}$
Chip Disable to Data Retention Time (see waveform below)	$t_{CDR}$	0	—	—	ns
Operation Recovery Time (see waveform below)	$t_{rec}$	$t_{AVAV}^*$	—	—	ns

\* $t_{AVAV}$  = Read Cycle Time



TYPICAL CHARACTERISTICS  
(Continued)

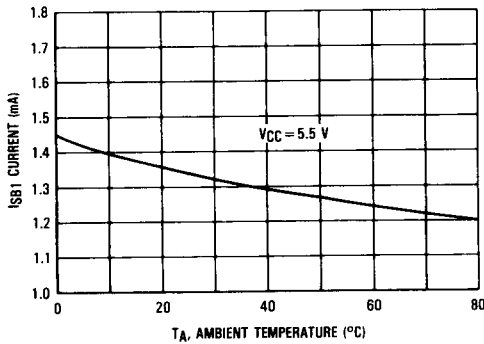


Figure 3. Standby Current Versus Temperature

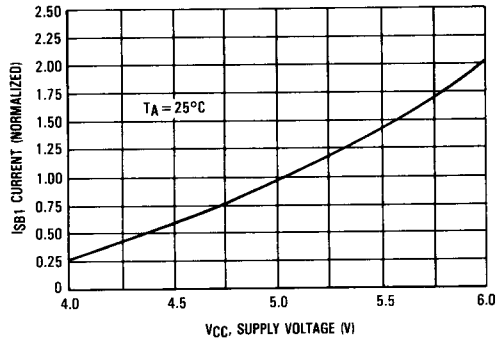


Figure 4. Standby Current Versus Supply Voltage

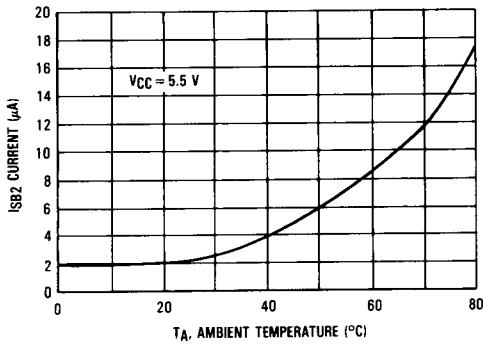


Figure 5. Standby Current Versus Temperature

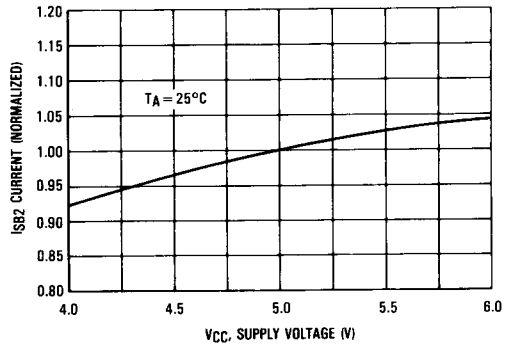


Figure 6. Standby Current Versus Supply Voltage

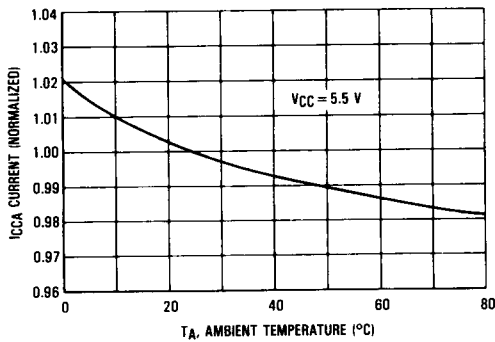


Figure 7. Supply Current Versus Temperature

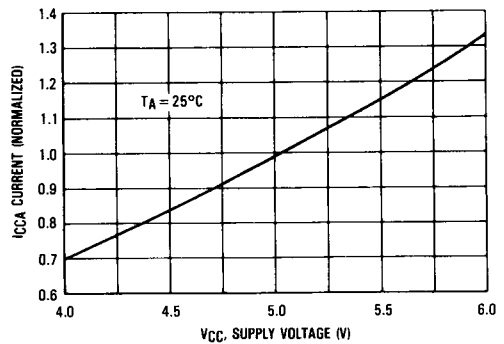


Figure 8. Supply Current Versus Supply Voltage

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TYPICAL CHARACTERISTICS  
(Continued)

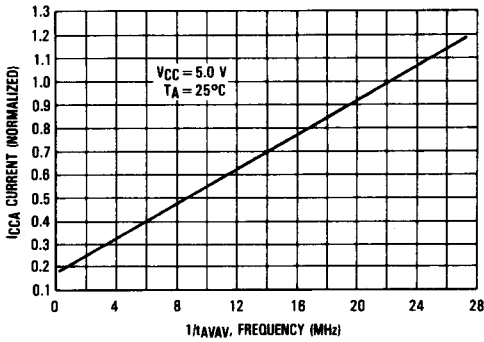


Figure 9. Supply Current Versus Frequency

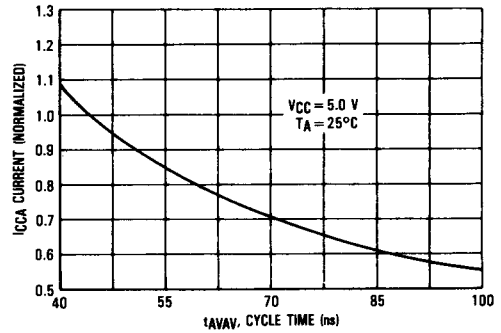


Figure 10. Supply Current Versus Cycle Time

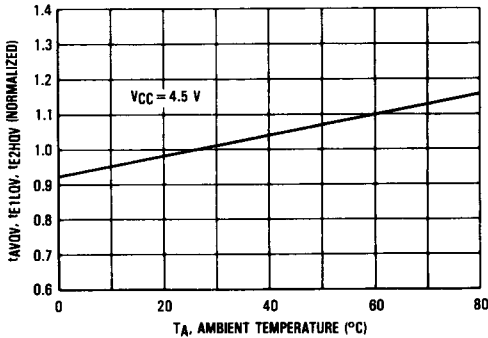


Figure 11. Access Time Versus Temperature

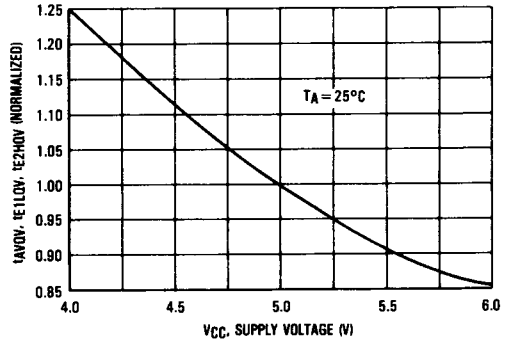


Figure 12. Access Time Versus Supply Voltage

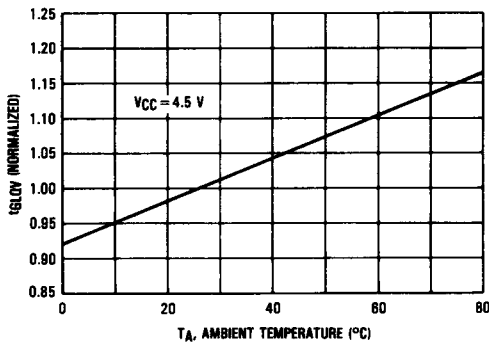


Figure 13. Access Time Versus Temperature

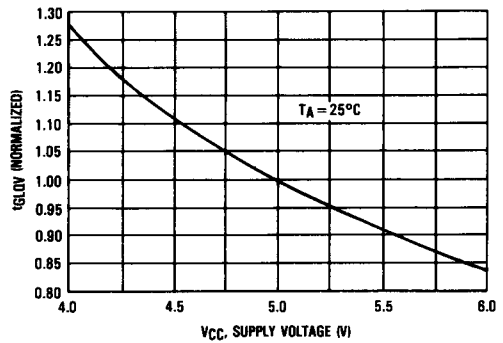


Figure 14. Access Time Versus Supply Voltage

# MCM6164•MCM61L64

## ORDERING INFORMATION (Order by Full Part Number)

